

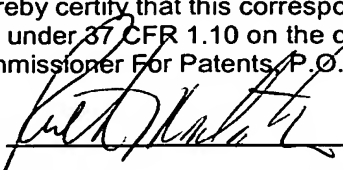
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Attorney's Docket No.: JG-SU-5213/500577.20067

U.S. Application No.:

International Application No.: PCT.JP2003/013320

International Filing Date: OCTOBER 17, 2003

17 OCTOBER 2003

Priority Date Claimed: OCTOBER 18, 2002

18 OCTOBER 2002

Title of Invention:

METHOD FOR MEASURING POINT DEFECT DISTRIBUTION
OF SILICON SINGLE CRYSTAL INGOT

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PRELIMINARY AMENDMENT

Sir:

The above-identified application is filed concurrently herewith, please amend the specification and claims as follows:

Amendments to the specification begin on page 2 of this paper.

Amendments to the claims are reflected in the listing of claims, which begin on page 3 of this paper.

Remarks / Arguments begin on page 8 of this paper.